

40V N-Channel Enhancement Mode MOSFET

Description

The AP150N04D uses advanced trench technology

to provide excellent R_{DS(ON)}, low gate charge and

operation with gate voltages as low as 4.5V. This

device is suitable for use as a

Battery protection or in other Switching application.

General Features

V_{DS} = 40V I_D =150 A

 $R_{DS(ON)} < 2.4m\Omega @ V_{GS}=10V$

Application

Battery protection

Load switch

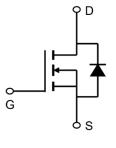
Uninterruptible power supply

Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)	
AP150N04D	TO-252-3L	AP150N04D XXX YYYY	2500	

Absolute Maximum Ratings (TC=25℃unless otherwise noted)

Symbol	Parameter	Rating	Units
VDS	Drain-Source Voltage	40	V
VGS	Gate-Source Voltage	±20	V
I⊵@Tc=25℃	Continuous Drain Current, V _{GS} @ 10V ^{1,6}	150	A
I _D @T _C =100℃	Continuous Drain Current, V _{GS} @ 10V ^{1,6}	90	A
IDM	Pulsed Drain Current ²	450	A
EAS	Single Pulse Avalanche Energy ³	400	mJ
IAS	Avalanche Current	40	A
P _D @T _C =25°C	Total Power Dissipation ⁴	125	W
TSTG	Storage Temperature Range	-55 to 150	°C
TJ	TJ Operating Junction Temperature Range		°C
R₀JA	R ₀ JA Thermal Resistance Junction-Ambient ¹		°C/W
R _θ JC	Thermal Resistance Junction-Case ¹	1	°C/W









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Electrical Characteristics (TJ=25°C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BVDSS	Drain-Source Breakdown Voltage	V_{GS} =0V , I _D =250uA	40			V
RDS(ON)	Static Drain-Source On-Resistance ²	V_{GS} =10V , I_D =20A		2.0	2.3	
RDS(ON)	Static Drain-Source On-Resistance ²	V _{GS} =4.5V , I _D =20A		2.7	3.0	mΩ
VGS(th)	Gate Threshold Voltage	$V_{GS}=V_{DS}$, $I_{D}=250uA$	1.2	1.6	2.2	V
IDSS	Drain-Source Leakage Current	$V_{\text{DS}}{=}32V$, $V_{\text{GS}}{=}0V$, $T_{\text{J}}{=}25^\circ\!\!\mathrm{C}$			1	uA
1033		$V_{\text{DS}}{=}32V$, $V_{\text{GS}}{=}0V$, $T_{\text{J}}{=}55^\circ\!\!\mathrm{C}$			5	uA
IGSS	Gate-Source Leakage Current	$V_{GS}=\pm 20V$, $V_{DS}=0V$			±100	nA
gfs	Forward Transconductance	V _{DS} =5V , I _D =20A		53		S
Rg	Gate Resistance	V _{DS} =0V , V _{GS} =0V , f=1MHz		1.0		Ω
Qg	Total Gate Charge (4.5V)			45		
Qgs	Gate-Source Charge	$V_{\text{DS}}{=}15V$, $V_{\text{GS}}{=}10V$, $I_{\text{D}}{=}20A$		12		nC
Qgd	Gate-Drain Charge			18.5		
Td(on)	Turn-On Delay Time			18.5		
Tr	Rise Time	V _{DD} =15V , V _{GS} =10V , R _G =3.3 ,		9		
Td(off)	Turn-Off Delay Time			58.5		ns
T _f	Fall Time	ID=20A		32		
Ciss	Input Capacitance			3972		
Coss	Output Capacitance	V _{DS} =20V , V _{GS} =0V , f=1MHz		1119		pF
Crss	Reverse Transfer Capacitance	1		82		
IS	Continuous Source Current ^{1,6}	$V_G=V_D=0V$, Force Current			100	А
VSD	Diode Forward Voltage ²	V _{GS} =0V , Is=1A , TJ=25℃			1.2	V

Note :

1. The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.

2.The data tested by pulsed , pulse width $\ \leq\$ 300us , duty cycle $\ \leq\$ 2%

3. The EAS data shows Max. rating . The test condition is V_{DD}=25V,V_{GS}=10V,L=0.5mH,I_{AS}=40A

4.The power dissipation is limited by $150\,^\circ\!\mathrm{C}$ junction temperature

5. The data is theoretically the same as I_D and I_{DM} , in real applications, should be limited by total power dissipation.



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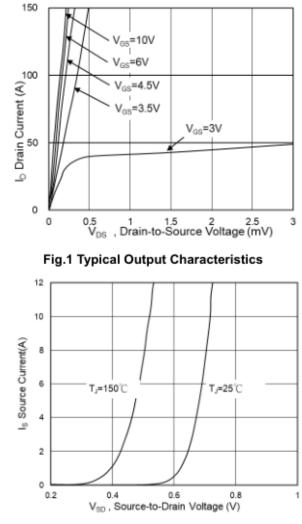


Fig.3 Source Drain Forward Characteristics

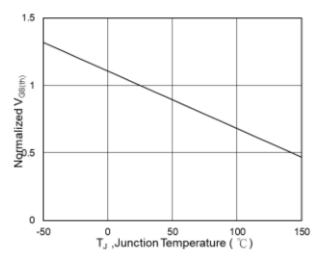
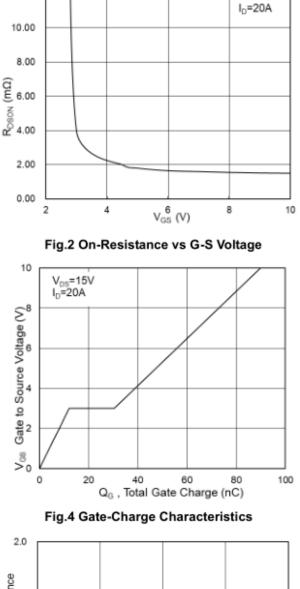


Fig.5 Normalized V_{GS(th)} vs T_J



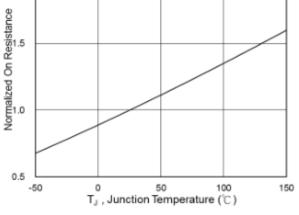
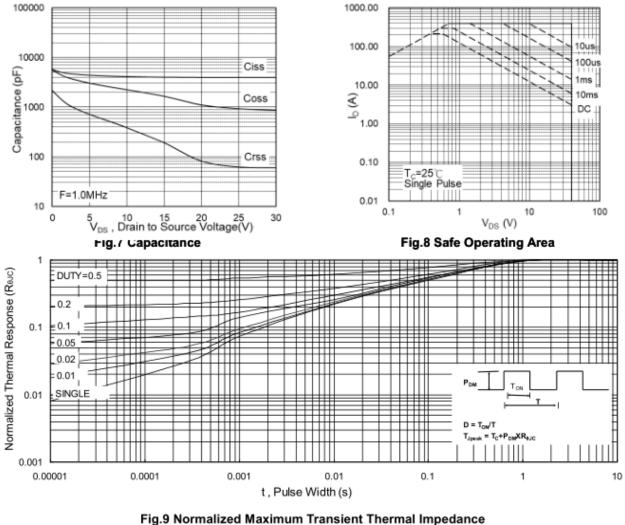


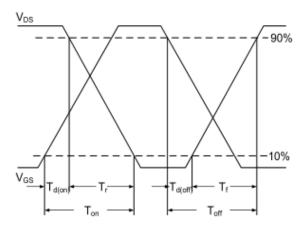
Fig.6 Normalized R_{DSON} vs T_J

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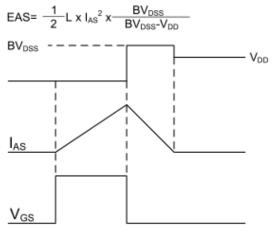


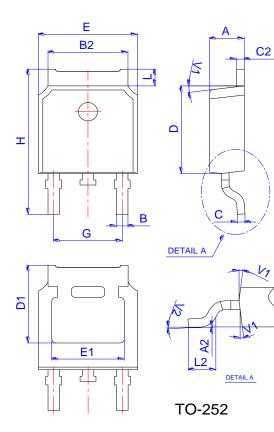
Fig.11 Unclamped Inductive Switching Waveform





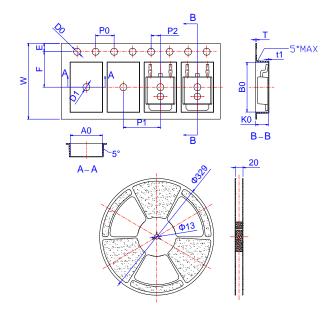
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Package Mechanical Data: TO-252-3L



	Dimensions					
Ref.	Millimeters			Inches		
	Min.	Тур.	Max.	Min.	Тур.	Max.
Α	2.10		2.50	0.083		0.098
A2	0		0.10	0		0.004
В	0.66		0.86	0.026		0.034
B2	5.18		5.48	0.202		0.216
С	0.40		0.60	0.016		0.024
C2	0.44		0.58	0.017		0.023
D	5.90		6.30	0.232		0.248
D1	5.30REF			0.209REF		
E	6.40		6.80	0.252		0.268
E1	4.63			0.182		
G	4.47		4.67	0.176		0.184
Н	9.50		10.70	0.374		0.421
L	1.09		1.21	0.043		0.048
L2	1.35		1.65	0.053		0.065
V1		7°			7°	
V2	0°		6°	0°		6°

Reel Spectification-TO-252



	Dimensions					
Ref.	Millimeters			Inches		
	Min.	Тур.	Max.	Min.	Тур.	Max.
W	15.90	16.00	16.10	0.626	0.630	0.634
Е	1.65	1.75	1.85	0.065	0.069	0.073
F	7.40	7.50	7.60	0.291	0.295	0.299
D0	1.40	1.50	1.60	0.055	0.059	0.063
D1	1.40	1.50	1.60	0.055	0.059	0.063
P0	3.90	4.00	4.10	0.154	0.157	0.161
P1	7.90	8.00	8.10	0.311	0.315	0.319
P2	1.90	2.00	2.10	0.075	0.079	0.083
A0	6.85	6.90	7.00	0.270	0.271	0.276
B0	10.45	10.50	10.60	0.411	0.413	0.417
K0	2.68	2.78	2.88	0.105	0.109	0.113
Т	0.24		0.27	0.009		0.011
t1	0.10			0.004		
10P0	39.80	40.00	40.20	1.567	1.575	1.583

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Edition	Date	Change
Rve1.0	2019/8/1	Initial release

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